

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE (L<sup>2</sup>-π-MOSV)

# 2SK2615

HIGH SPEED, HIGH CURRENT SWITCHING APPLICATIONS  
DC-DC CONVERTER, RELAY DRIVE AND MOTOR DRIVE APPLICATIONS

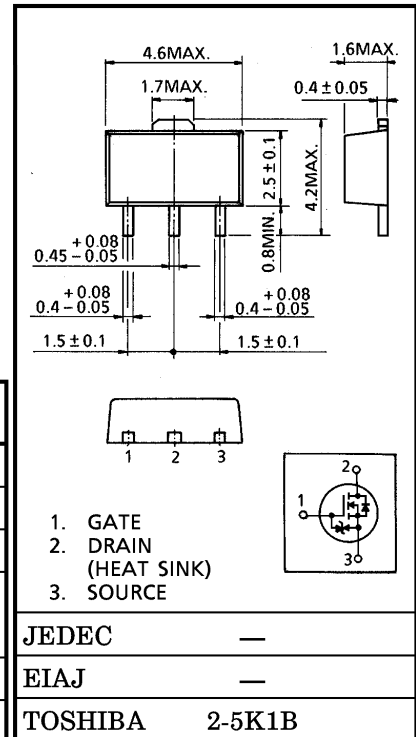
INDUSTRIAL APPLICATIONS

Unit in mm

- Low Drain-Source ON Resistance :  $R_{DS(ON)} = 0.23\Omega$  (Typ.)
- High Forward Transfer Admittance :  $|Y_{fs}| = 2.0S$  (Typ.)
- Low Leakage Current :  $I_{DSS} = 100\mu A$  (Max.) ( $V_{DS} = 60V$ )
- Enhancement-Mode :  $V_{th} = 0.8 \sim 2.0V$  ( $V_{DS} = 10V, I_D = 1mA$ )

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	$V_{DSS}$	60	V
Drain-Gate Voltage ( $R_{GS} = 20k\Omega$ )	$V_{DGR}$	60	V
Gate-Source Voltage	$V_{GSS}$	±20	V
Drain Current	DC	$I_D$	2
	Pulse	$I_{DP}$	6
Drain Power Dissipation (Ta = 25°C)	$P_D$	0.5	W
Drain Power Dissipation	$P_D^*$	1.5	W
Channel Temperature	$T_{ch}$	150	°C
Storage Temperature Range	$T_{stg}$	-55~150	°C



Weight : 0.05g (Typ.)

MARKING



\* : Mounted on ceramic substrate (600mm<sup>2</sup> × 0.8t)

THERMAL CHARACTERISTICS

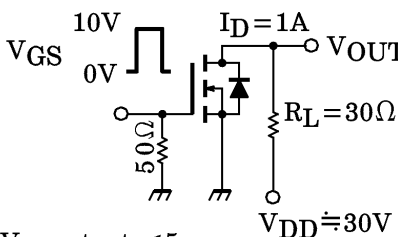
CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Ambient	$R_{th(ch-a)}$	250	°C/W

**This transistor is an electrostatic sensitive device.  
Please handle with caution.**

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## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		$I_{GSS}$	$V_{GS} = \pm 16V, V_{DS} = 0V$	—	—	$\pm 10$	$\mu A$
Drain Cut-off Current		$I_{DSS}$	$V_{DS} = 60V, V_{GS} = 0V$	—	—	100	$\mu A$
Drain-Source Breakdown Voltage		$V_{(BR)DSS}$	$I_D = 10mA, V_{GS} = 0V$	60	—	—	V
Gate Threshold Voltage		$V_{th}$	$V_{DS} = 10V, I_D = 1mA$	0.8	—	2.0	V
Drain-Source ON Resistance		$R_{DS(ON)}$	$V_{GS} = 4V, I_D = 1A$	—	0.33	0.44	$\Omega$
			$V_{GS} = 10V, I_D = 1A$	—	0.23	0.30	
Forward Transfer Admittance		$ Y_{fs} $	$V_{DS} = 10V, I_D = 1A$	1.0	2.0	—	S
Input Capacitance		$C_{iss}$	$V_{DS} = 10V, V_{GS} = 0V, f = 1MHz$	—	150	—	pF
Reverse Transfer Capacitance		$C_{rss}$		—	25	—	
Output Capacitance		$C_{oss}$		—	70	—	
Switching Time	Rise Time	$t_r$	 <p><math>V_{GS} = 10V, 0V</math>  <math>I_D = 1A</math>  <math>R_L = 30\Omega</math>  <math>V_{DD} \doteq 30V</math></p> <p><math>V_{IN} : t_r, t_f &lt; 5ns,</math>  <math>Duty \leq 1\%, t_w = 10\mu s</math></p>	—	25	—	ns
	Turn-on Time	$t_{on}$		—	30	—	
	Fall Time	$t_f$		—	50	—	
	Turn-off Time	$t_{off}$		—	150	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		$Q_g$	$V_{DD} \doteq 48V, V_{GS} = 10V, I_D = 2A$	—	6.0	—	nC
Gate-Source Charge		$Q_{gs}$		—	4.6	—	
Gate-Drain ("Miller") Charge		$Q_{gd}$		—	1.4	—	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	$I_{DR}$	—	—	—	2	A
Pulse Drain Reverse Current	$I_{DRP}$	—	—	—	6	A
Diode Forward Voltage	$V_{DSF}$	$I_{DR} = 2A, V_{GS} = 0V$	—	—	-1.5	V
Reverse Recovery Time	$t_{rr}$	$I_{DR} = 2A, V_{GS} = 0V$	—	100	—	ns
Reverse Recovered Charge	$Q_{rr}$	$dI_{DR} / dt = 50A / \mu s$	—	40	—	$\mu C$

